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|-----------------------------------|--|-------------------------|---|--|
| Notice of References Cited | | Application/Control No. | Applicant(s)/Patent Under Reexamination | |
| | | 10/762,536 | SUH ET AL. | |
| Examiner Thomas M. Ho | | Art Unit 2132 | Page 1 of 1 | |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|---------------------|----------------|
| * | A | US-6,021,199 | 02-2000 | Ishibashi, Yasuhiro | 380/217 |
| * | B | US-6,550,009 | 04-2003 | Uranaka et al. | 713/168 |
| * | C | US-6,664,526 | 12-2003 | Yokoi, Kenya | 250/201.5 |
| * | D | US-5,689,486 | 11-1997 | Shimizu et al. | 369/47.24 |
| * | E | US-6,519,213 | 02-2003 | Song et al. | 369/44.26 |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|-----------------------------------|---|--|-----------------|---------|------|----------------|
| | N | EP 1067540 A2 | 10/01/2001 | | | |
| | O | | | | | |
| Change(s) applied to document; | P | | | | | |
| /J.I.W./ | Q | | | | | |
| 5/12/2011 | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| | | |
|---|---|---|
| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.